

## Preliminary Product Specification

| Rev. 0.85|

**G2**      **Silver****Industrial 2.5" SATA SSD datasheet****120GB – 1920B**

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## 1. Product Summary

<u>Capacity Range</u>	<b>120GB – 1920GB</b>
<u>Form Factor</u>	<b>2.5"</b>
<u>Host Interface</u>	<b>SATA Rev. 3.2</b> <b>SATA 3.0 6Gb/s</b> Backward compatible to SATA 3Gb/s, 1.5Gb/s
<u>Performance</u>	<b>Sequential read: up to 550 MB/s</b> <b>Sequential write: up to 510 MB/s</b> <b>Random read: up to 96.5K IOPS</b> <b>Random write: up to 86.5 IOPS</b>
<u>Reliability</u>	<b>MTBF: 2 million hours</b> <b>UBER: &lt;1 sector / 10<sup>16</sup> bits read</b>
<u>Operating Temperature</u>	<b>Commercial: 0°C ~ 70°C</b> Or <b>Industrial: -40°C ~ 85°C</b>
<u>Storage Temperature</u>	<b>-40°C ~ 85°C</b>
<u>Special Features</u>	<b>Thermal throttling</b> <b>Security: AES256</b> <b>Thermal Monitor</b> <b>TCG OPAL2.0(optional)</b>
<u>Compliances</u>	<b>RoHS*, CE*, FCC*, WEEE*</b> *Note: Please contact with Intelligent Memory represent for the detail of compliance conformity.

## 2. Order Information

Table 1 – Part Numbers

Part Number	Capacity	Operating Temperature range
IMS325B1M2A2A1C3A9A0000	120GB	0°C ~ 70°C
IMS325B3M2A2A1C3B2A0000	240GB	
IMS325B5M2A2A1C3B4A0000	480GB	
IMS325B7M2A2A1C3B6A0000	960GB	
IMS325B9M2A2A1C3B8A0000	1920GB	
IMS325B1M2A2A1I3A9A0000	120GB	-40°C ~ 85°C
IMS325B3M2A2A1I3B2A0000	240GB	
IMS325B5M2A2A1I3B4A0000	480GB	
IMS325B7M2A2A1I3B6A0000	960GB	
IMS325B9M2A2A1I3B8A0000	1920GB	

### 3. Product Information

I'M's 2.5" SATA SSD product family features a SATA III interface and offers reliable high speed data throughput in various access modes. It is available in capacities up to 7680GB, with customizable settings for Overprovisioning or Thermal Throttling.

#### 3.1 Block Diagram

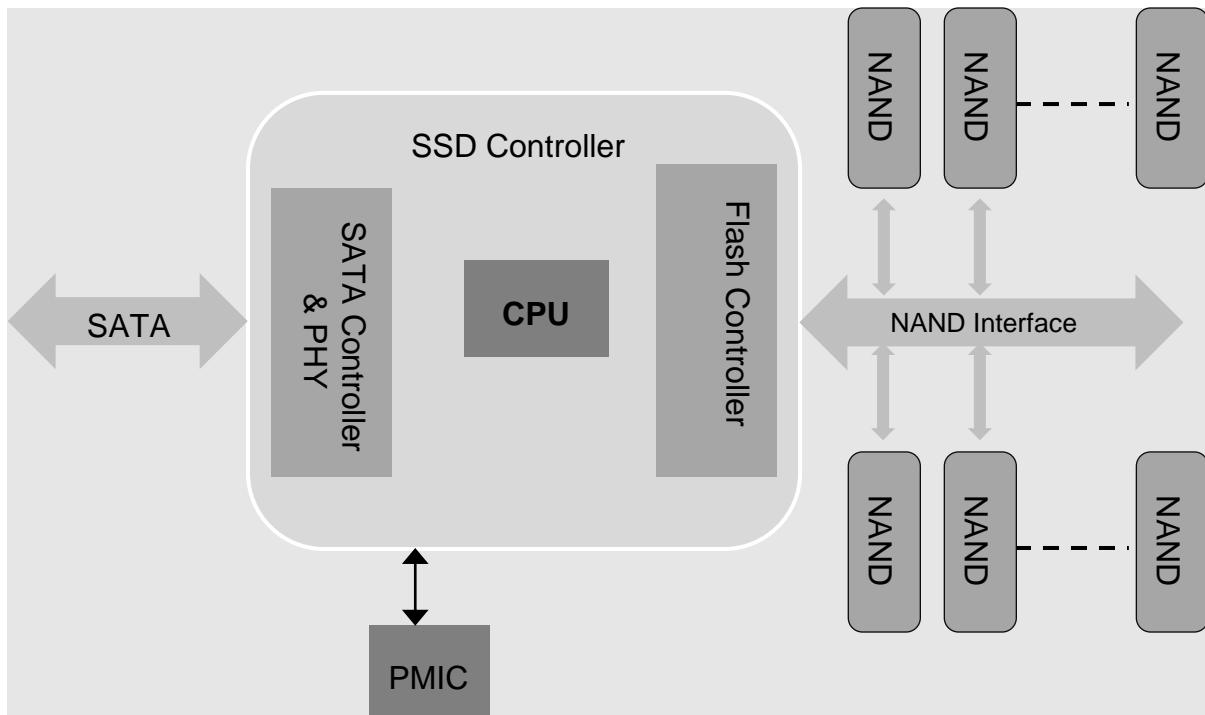


Figure 1 – Block Diagram

## 3.2 Product Features

### Electrical/Physical Interface: SATA

- Compliant with SATA Revision 3.2.
- Compatible with SATA 1.5Gbps, 3Gbps and 6Gbps interface.
- Supports expanded register for SATA protocol 48 bits addressing mode.
- Supports power management.

### Advanced Flash Management Features

#### **LDPC ECC (Low Density Parity Check Error Correction Code)**

The deterioration of the flash memory cell over time and the disruptions from neighboring flash memory pages can lead to random bit errors in the stored data. While the chances of any given data bit being corrupted is quite small, the vast number of data bits in a storage system makes the likelihood of data corruption a very real possibility. Error detection and correction codes are used in flash memory storage systems to protect the data from corruption.

#### **Static and Dynamic Wear Leveling**

Wear leveling is a process that helps reduce premature wearing out of NAND Flash devices. The Flash controller manages access to the NAND Flash memory devices and determines how the NAND Flash blocks are used. In most cases, the NAND Flash controller maintains a lookup table to translate the memory array's physical block address (PBA) to the logical block address (LBA) used by the host system known as Physical to Logical Address Translation Table.

#### **Bad Block Management**

Bad blocks are blocks that include one or more invalid bits, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as "Initial Bad Blocks". Bad blocks that are developed during the lifespan of the flash are named "Later Bad Blocks"

#### **S.M.A.R.T. functionality**

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a hard disk drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

#### **Overprovision**

Over provisioning is a technique used in the design of flash SSDs and flash media cards. By providing extra memory capacity (which the user can't access) the SSD controller can more easily create pre-erased blocks ready to be used in the virtual pool.

Overprovisioning improves:

- Write performance & IOPS
- Reliability & endurance

### **Thermal Throttling**

Thermal throttling is designed to prevent any components in a SSD from over-heating during read and write operations. Intelligent Memory SSD implemented an on-die thermal sensor and with its accuracy; firmware can apply different levels of throttling to achieve the purpose of protection efficiently and proactively via temperature monitoring.

### **Security Features**

#### **Secure Erase**

#### **PSID (Optional for TCG OPAL 2.0)**

#### **Quick Erase (Optional)**

#### **Write Protection (Optional)**

### **Low Power management**

#### **DEVSLP Mode (Optional)**

#### **HIPM/DIPM Mode**

### **Lifetime & Endurance Management**

#### **Terabytes Written (TBW)**

#### **Media Wear Indicator**

## 4. Product Specification

### 4.1 Performance

We specify the performance of our NAND products as below:

- “Peak” describes the measured performance when the product is new and unused. It is commonly used by vendors in their datasheets. However, SSDs by design reduce performance after a relatively short usage period, so peak values cannot be used to predict an application’s longer-term performance.

We are specifying peak performance for easier comparison of I'M's products with other solutions but recommend considering sustained performance values when selecting the most suitable solution for an application. Further detail can also be found in our whitepaper on performance ([hyperlink](#))

Table 2 – Peak Performance

Capacity	Sequential performance		Random Performance	
	Read (MB/s)	Write (MB/s)	4K Read (IOPS)	4K Write (IOPS)
120GB	550	450	44.5K	79.5K
240GB	550	485	75.5K	82.5K
480GB	550	500	91.5K	85K
960GB	550	510	96.5K	86.5K
1,920GB	550	510	93.5K	86K

Notes:

1. Peak performance measured in **Fresh Out of the Box (FOB)** condition
2. Sequential performance is measured with 128KB transfer size; QD32 and 4KB align with IO Meter.
3. Random performance tested with IO Meter: 4KB random write with QD32.
4. Performance may differ depending on application and platform.

## 4.2 Endurance and Reliability

### 4.2.1 Endurance

The lifetime of our NAND products is specified in TBW, i.e. the total amount of data that the host can write to the NAND media in a defined pattern. In our case this pattern is based on the workload definitions set by JEDEC in JESD219A.

Same as for performance, endurance specification varies greatly depending on the underlying assumptions (especially also if the formula set by JEDEC, including the guard band is used) and I'M recommend assuring these assumptions are the same when comparing TBW values of different products.

Our endurance whitepaper is available here and offers a simple calculator to validate and analyze different endurance values

Table 3 – TeraBytes Written

Capacity	TBW	TBW with guard band
120GB	180	90
240GB	360	180
480GB	720	360
960GB	1440	720
1,920GB	2880	1440
<b>Notes:</b>		
1. TBW values are specified based on JEDEC 218 client workload		
2. Actual lifetime may vary depending on platform and application		
<b>Note:</b> JEDEC specifies to consider guard band of 2 for calculating the TBW as a wear levelling factor as industrial applications need more rigid working conditions.		

### 4.2.2 Reliability

Table 4 – Reliability

Parameter	Value
UBER	Uncorrectable Bit Error Rate (UBER) < 1 sector per $10^{16}$ bits read
MTBF	2,000,000 Hours

## 4.3 Power Supply

Table 5 – Supply Voltage

Supply Voltage	
Parameter	Rating
Operative Voltage	5.0V, +/-5%
Rise Time (Max/Min)	100ms/0.1ms
Fall Time (Max/Min)	5s/1ms
Min. Off Time*1	1s
Notes *1: Minimum time between power removed from SSD (Vcc < 100 mW) and power re-applied to the drive	

## 4.4 Power Consumption

Table 6 – Power Consumption

Capacity	Read	Write	Partial	Slumber	Idle
	Avg.	Avg.	Avg.	Avg.	Max.
120GB	1,100	1,150	50	15	210
240GB	1,150	1,300	52	15	210
480GB	1,250	1,520	52	15	210
960GB	1,350	1,730	55	16	215
1,920GB	1,500	1,750	55	17	215

## 5. Environmental Specifications

### 5.1 Temperature and Humidity

Table 7 – High Temperature Test Condition

High Temperature Test			
Test Item		Temperature Standard/Wide Temp	Humidity
High Temperature Test	Operation	70°C/85°C	0% RH
	Storage	85°C	0% RH
Low Temperature Test	Operation	0°C /-40°C	0% RH
	Storage	-40°C	0% RH
High Humidity Test	Operation	40°C	90% RH
	Storage	40°C	93% RH
Temperature Cycle Test	Operation	0°C-70°C/-40°C-85°C	—
	Storage	-40°C ~ 85°C	—
Notes: 1. Operation temperature is measured by device temperature sensor. Airflow is suggested and it will allow device to be operated at appropriate temperature for each component during heavy workloads environment.			

### 5.2 Shock and Vibration

Table 8 – Mechanical Test Condition

Items			Condition
Shock	Operating	Acceleration Force	50G, (11ms duration, half sine wave)
	Non-operating		1500G, (0.5ms duration, half sine wave)
Vibration	Non-operating	Frequency/Acceleration	10Hz~2000Hz(peak)/10G

### 5.3 EMC

Table 9 – EMC Compliance

Items		Condition
ESD Compliance		EN 55024, CISPR 24 EN 61000-4-2 IEC 61000-4-2
EMI Compliance		EN 55032, CISPR 32(CE) CSN 13438 (BSMI) ANSI C63.4 (FCC) VCCI-CISPR 32 (VCCI)

## 6. Interface

### 6.1 Pin Assignment and Descriptions

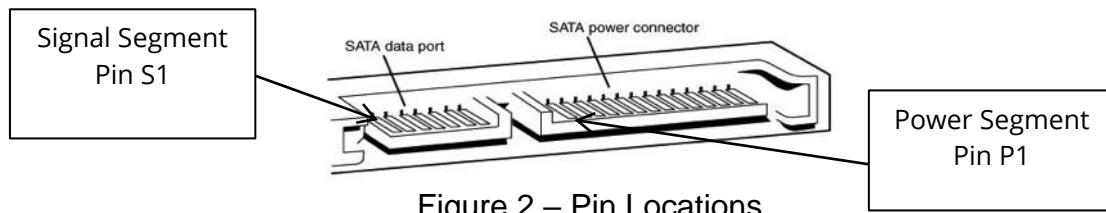


Figure 2 – Pin Locations

Table 10 – Signal Segment Pin Assignment and Descriptions

Pin #	Function
S1	GND
S2	A+ (Differential Signal Pair A)
S3	A – (Differential Signal Pair A)
S4	GND
S5	B – (Differential Signal Pair B)
S6	B+ (Differential Signal Pair B)
S7	GND

Table 11 – Power Segment Pin Assignment and Descriptions

Pin #	Function
P1	Not Used (3.3V)
P2	Not Used (3.3V)
P3	DEVSLP (not support)
P4	GND
P5	GND
P6	GND
P7	5V pre-charge
P8	5V
P9	5V
P10	GND
P11	Reserved
P12	GND
P13	Not Used (12V pre-charge)
P14	Not Used (12V)
P15	Not Used (12V)

## 7. Physical Dimensions

100.00mm(L) x 69.85mm(W) x 7.00mm(H)

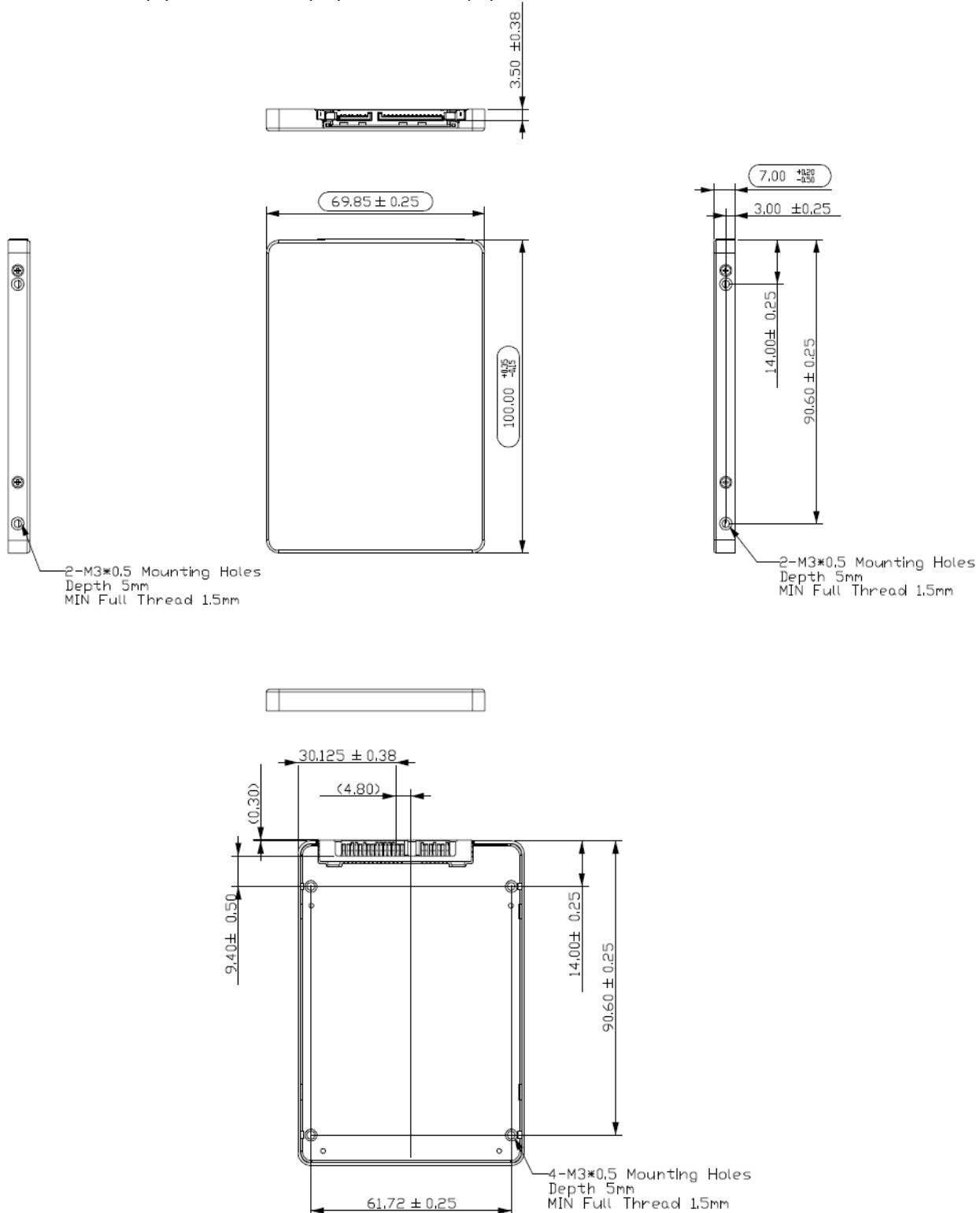


Figure 3 – Device Physical Dimension

## 8. Command Set

### 8.1 Supported Command List

Table 12 – ATA Command List

Description	Op Code			Description		Op Code		
CFA Write Sectors Without Erase	38h			Recalibrate		10h-1Fh		
Check Power Mode	E5h			Sanitize		B4h		
Data Set Management	06h			Security Disable Password		F6h		
Device Configuration	B1h			Security Erase Prepare		F3h		
Disable Device Automatic Partial to Slumber transitions	Efh	90h	07h	Security Erase Unit		F4h		
Disable Device Sleep	Efh	90h	09h	Security Freeze Lock		F5h		
Disable Device-initiated interface power state (DIPM) transitions	Efh	90h	03h	Security Set Password		F1h		
Disable DMA Setup FIS Auto-Activate optimization	Efh	90h	02h	Security Unlock		F2h		
Disable read look-ahead	Ffh	55h		Seek		70h-7Fh		
Disable reverting to power-on defaults	Efh	66h		Set Features		Efh		
Disable Software Settings Preservation (SSP)	Efh	90h	06h	Set Max Address		F9h		
Disable the APM feature set	Efh	85h		SET MAX FREEZE LOCIK		F9h 04h		
Disable use of SATA feature set	Feh	90h		SET MAX SET PASSWORD		F9h 01h		
Disable volatile write cache	Efh	82h		SET MAX UNLOCK		F9h 03h		
Download Microcode	92h			SET MAXLOCK		F9h 02h		
Download Microcode DMA	93h			Set Multiple Mode		C6h		
Enable Device Automatic Partial to Slumber transitions	Efh	10h	07h	Set Native Max Address EXT		37h		
Enable Device Sleep	Efh	10h	09h	Set transfer mode		Efh 03h		
Enable Device-initiated interface power state (DIPM) transitions	Efh	10h	03h	Sleep		E6h		
Enable DMA Setup FIS Auto-Activate optimization	Efh	10h	02h	SMART		B0h		
Enable read look-ahead	Efh	Aah		SMART DISABLE OPERATIONS		B0h D9h		
Enable reverting to power-on defaults	Efh	Cch		SMART ENABLE OPERATIONS		B0h D8h		
Enable Software Settings Preservation (SSP)	Efh	10h	06h	SMART ENABLE/DISABLE ATTRIBUTE AUTOSAVE		B0h D2h		
Enable the APM feature set	Efh	05h		SMART ENABLE/DISABLE AUTOMATIC OFF-LINE		B0h Dbh		
Enable use of SATA features et	Efh	10h		SMART EXECUTE OFF-LINE IMMEDIATE		B0h D4h		
Enable volatile write cache	Efh	02h		SMART READ ATTRIBUTE THRESHOLDS		B0h D1h		
Execute Device Diagnostic	90h			SMART READ DATA		B0h D0h		
Flush Cache	E7h			SMART READ LOG		B0h D5h		

Flush Cache EXT	Eah	SMART RETURN STATUS	B0h	Dah
Identify Device	Ech	SMART SAVE ATTRIBUTE VALUES	B0h	D3h
Idle	E3h	SMART WRITE LOG	B0h	D6h
Idle Immediate	E1h	Standby		E2h
Initialize Device Parameters	91h	Standby Immediate		E0h
NOP	00h	Write Buffer		E8h
Read Buffer	E4h	Write Buffer DMA		Ebh
READ BUFFER DMA	E9h	Write DMA		Cah
Read DMA	C8h	Write DMA EXT		35h
Read DMA EXT	25h	Write DMA FUA EXT		3Dh
Read DMA without Retry	C9h	Write DMA without Retry		Cbh
Read FPDMA Queued	60h	Write FPDMA Queued		61h
Read Log DMA EXT	47h	Write Log DMA EXT		57h
Read Log EXT	2Fh	Write Long EXT		3Fh
Read Multiple	C4h	Write Multiple		C5h
Read Multiple EXT	29h	Write Multiple EXT		39h
Read Native Max Address	F8h	Write Multiple FUA EXT		Ceh
Read Native Max Address EXT	27h	Write Sectors		30h
Read Sectors	20h	Write Sectors EXT		34h
Read Sectors EXT	24h	Write Sectors without Retry		31h
Read Sectors without Retry	21h	Write Uncorrectable EXT		45h
Read Verify Sectors	40h	Zero EXT		44h
Read Verify Sectors EXT	42h			
Read Verify Sectors without Retry	41h			

## 8.2 Identify Device Data

Table 13 – Return Data of Identify Device Command

Word	F : Fixed V : Variable X : Both	Default Value	Description
0	F	0040h	General configuration bit-significant information
1	X	*1	Obsolete – Number of logical cylinders
2	V	C837h	Specific configuration
3	X	0010h	Obsolete – Number of logical heads (16)
4-5	X	00000000h	Retired
6	X	003Fh	Obsolete – Number of logical sectors per logical track(63)
7-8	V	00000000h	Reserved for assignment by the Compact Flash Association
9	X	0000h	Retired
10-19	F	Varies	Serial number (20 ASCII characters)

20-21	X	0000h	Retired
22	X	0000h	Obsolete
23-26	F	Varies	Firmware revision (8 ASCII characters)
27-46	F	Varies	Model number (xxxxxxxx)
47	F	8010h	7:0- Maximum number of sectors transferred per interrupt on MULTIPLE commands
48	F	4000h	Trusted Computing feature set options(not support)
49	F	2F00h	Capabilities
50	F	4000h	Capabilities
51-52	X	000000000h	Obsolete
53	F	0007h	Words 88 and 70:64 valid
54	X	*1	Obsolete – Number of logical cylinders
55	X	0010h	Obsolete – Number of logical heads (16)
56	X	003Fh	Obsolete – Number of logical sectors per track (63)
57-58	X	*2	Obsolete – Current capacity in sectors
59	F	DD10h	Number of sectors transferred per interrupt on MULTIPLE commands
60-61	F	*3	Maximum number of sector ( 28bit LBA mode)
62	X	0000h	Obsolete
63	F	0407h	Multi-word DMA modes supported/selected
64	F	0003h	PIO modes supported
65	F	0078h	Minimum Multiword DMA transfer cycle time per word
66	F	0078h	Manufacturer's recommended Multiword DMA transfer cycle time
67	F	0078h	Minimum PIO transfer cycle time without flow control
68	F	0078h	Minimum PIO transfer cycle time with IORDY flow control
69	F	1F00h	Additional Supported (support download microcode DMA)
70	F	0000h	Reserved
71-74	F	0000000000000000000h	Reserved 17ft he17 IDENTIFY PACKET DEVICE command
75	F	001Fh	Queue depth
76	F	C50Eh	Serial SATA capabilities
77	F	0006h	Serial ATA Additional Capabilities
78	F	044Ch	Serial ATA features supported
79	V	0040h	Serial ATA features enabled
80	F	0FF8h	Major Version Number
81	F	0000h	Minor Version Number
82	F	746Bh	Command set supported
83	F	7D09h	Command set supported
84	F	4163h	Command set/feature supported extension
85	V	7469h	Command set/feature enabled
86	V	BC01h	Command set/feature enabled
87	V	4163h	Command set/feature default
88	V	007Fh	Ultra DMA Modes
89	F	000Ah	Time required for security erase unit completion

90	F	001Eh	Time required for Enhanced security erase completion
91	V	0000h	Current advanced power management value
92	V	FFFEh	Master Password Revision Code
93	F	0000h	Hardware reset result. The contents 18ft he bits (12:0) of this word can be changed only during the execution of hardware reset.
94	V	0000h	Vendor's recommended and actual acoustic management value
95	F	0000h	Stream Minimum Request Size
96	V	0000h	Streaming Transfer Time – DMA
97	V	0000h	Streaming Access Latency – DMA and PIO
98-99	F	0000h	Streaming Performance Granularity
100-103	V	*4	Maximum user LBA for 48 bit Address feature set
104	V	0000h	Streaming Transfer Time – PIO
105	F	0008h	Maximum number of 512-byte blocks per DATA SET MANAGEMENT command
106	F	4000h	Physical sector size/Logical sector size
107	F	0000h	Inter-seek delay for ISO-7779 acoustic testing in microseconds
108-111	F	0000000000000000h	Unique ID
112-115	F	0000000000000000h	Reserved
116	V	0000h	Reserved
117-118	F	00000000h	Words per logical Sector
119	F	4018h	Supported settings
120	F	4018h	Command set/Feature Enabled/Supported
121-126	F	0000h	Reserved
127	F	0000h	Removable Media Status Notification feature set support
128	V	0021h	Security status
129-140	X	0000h	Vendor specific
141	X	0000h	Vendor specific
142-159	X	0000h	Vendor specific
160	F	00000h	Compact Flash Association (CFA) power mode 1
161-167	X	00000h	Reserved for assignment by the CFA
168	F	3h 2.5 inch 4h 1.8 inch 5h Less than 1.8 inch	Device Nominal Form Factor
169	F	0001h	DATA SET MANAGEMENT command is supported
170-173	F	0000h	Additional Product Identifier
174-175	X	0000h	Reserve
176-205	V	0000h	Current media serial number
206	F	0000h	SCT Command Transport
207-208	F	0000h	Reserved
209	F	4000h	Alignment of logical blocks within a physical block
210-211	V	0000h	Write-Read-Verify Sector Count Mode 3 (not support)
212-213	F	0000h	Write-Read-Verify Sector Count Mode 2 (not support)
214-216	X	0000h	NV Cache relate (not support)

217	F	0001h	Non-rotating media device
218	F	0000h	Reserved
219	F	0000h	NV Cache relate (not support)
220	V	0000h	Write read verify feature set current mode
221	X	0000h	Reserved
222	F	107Fh	Transport major version number
223	F	0000h	Transport minor version number
224-229	X	0000h	reserved
230-233	F	0000h	Extend number of user addressable sectors
234	F	0001h	Minimum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h
235	F	FFFEh	Maximum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h
236-242	X	0000h	Reserved
243	F	0000h	Security Feature 4000:Self Encrypting Drive
244-254	F	0000h	Reserved
255	X	XXA5h XX is variable	Integrity word (Checksum and Signature)

Table 14 –List of Device Identification for Each Capacity

Capacity (GB)	*1 (Word 1 / Word 54)	*2 (Word 57 – 58)	*3 (Word 60 – 61)	*4 (Word 100 – 103)
120	3FFFh	FBFC10h	DF94BB0h	DF94BB0h
240	3FFFh	FBFC10h	FFFFFFFh	1BF244B0h
480	3FFFh	FBFC10h	FFFFFFFh	37E436B0h
960	3FFFh	FBFC10h	FFFFFFFh	6FC81AB0h
1,920	3FFFh	FBFC10h	FFFFFFFh	DF8FE2B0h
3,840	3FFFh	FBFC10h	FFFFFFFh	1BF1F72B0h
7,680	3FFFh	FBFC10h	FFFFFFFh	37E3E92B0h

## 9. Revision History

Revision	Descriptions	Release Date
0.1	Preliminary release	Apr, 2022
0.85	Performance and Endurance values updated	May, 2022

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